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(54) **Title:** CALIBRATION DEVICE

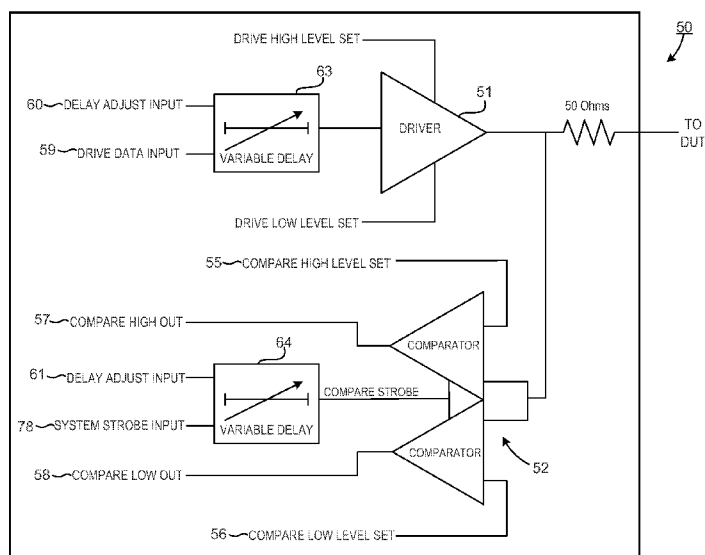


FIG. 3

(57) **Abstract:** An example apparatus is for use in calibration of a test system having multiple channels and a socket for receiving a device under test. The example apparatus includes a device interface that is connectable to the socket; and multiple circuit paths, where each circuit path is connectable, through the device interface, to a corresponding channel of the test system and being connected to a common node. The example apparatus is configured so that, during calibration, signals either (i) each pass from the test system, through one of the multiple circuit paths, and back to the test system through others of the multiple circuit paths, or (ii) each pass from the test system, through the others of the multiple circuit paths, and back to the test system through the one of the multiple circuit paths.